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	Applicant:	
	Hardayal Singh Gill et al.	
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U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
WK	A	6,117,690	09/12/2000	Bennett et al.	438	3	02/01/1999
WK	B	5,965,283	10/12/1999	Solin et al.	428	692	10/12/1999
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Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
WK	G	01/41214 A1	06/07/2001	WO	HO1L	23/58		

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
WK	H	Solin, S.A. et al; Enhanced Room-Temperature Geometric Magnetoresistance in Inhomogeneous Narrow-Gap Semiconductors, SCIENCE Vol. 289, 09/01/2000. ✓
WK	I	Solin, S.A. et al; Enhanced Room-Temperature Geometric Magnetoresistance in Inhomogeneous Narrow-Gap Semiconductors, The Magnetic Recording Conference, August 20-22, 2001
WK	J	Isai, Masaaki et al; Preparation and Crystal Properties of Thin InSb Films for Highly Sensitive Magnetoresistance Elements, Journal of Materials Research, 1986
WK	K	Chi, C. et al; Gradiometer Hall Probe, IBM Technical Disclosure Bulletin, Vol. 37 04/1994
WK	L	Gambino, R. et al; Improved Magnetoresistive Sensor, IBM Technical Disclosure Bulletin, Vol. 38, No. 08, August 1995
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Examiner <i>Will J. Ky</i>		Date Considered <i>9-15-03</i>

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.